

THE MICROSCOPIC UNIVERSE OF FEI

FEI Company is a leading supplier of ion and electron beam microscopes to a broad range of nanotechnology markets. FEI's products are focused on four major markets: NanoResearch, NanoIndustry including companies primarily performing research and development in material science; NanoBiology comprising institutes, companies and hospitals working in life sciences research and development, and NanoElectronics serving the semiconductor, data storage and related industries.

For over a decade FEI has led the development of DualBeam™ systems, which combine ion and electron beams in one system to provide 3D characterization, analysis and manipulation capabilities with resolution down to the sub-Ångstrom level.

FEI's most recent development, The Phenom, has broken ground by bringing electron microscopy to the mainstream. The Phenom is table top imaging system that produces high resolution images with limited operator training and facilities.

With R&D centers in North America and Europe and sales and service operations in more than 50 countries around the world, FEI is bringing the nanoscale within the grasp of leading researchers and manufacturers and helping to turn some of the biggest ideas of this century into reality.



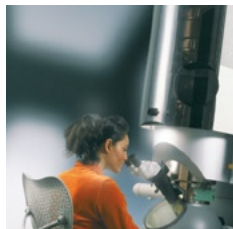
PHENOM™
THE PERFECT COMBINATION



COMPANY PROFILE

 FEI COMPANY™

Solutions for Enhanced Performance



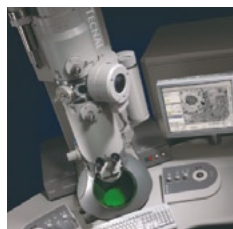
Titan™

Incorporates a newly designed platform dedicated to the principles of ultimate stability, ultimate performance and ultimate flexibility for corrector and monochromator technology and its applications. Conquering the sub-Ångström era.



Quanta™ 3D

DualBeam™ for 3D material characterization, industrial failure analysis and process control. Any sample, all data, any dimension.



Tecnai™ G2 Series

The next generation, award-winning, all-in-one, high performance TEM. Understanding decreasing dimensions.



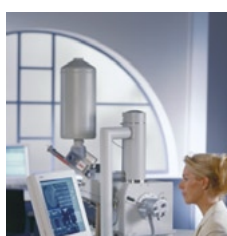
Nova™ NanoSEM Series

Ultra-high resolution FEG SEM for structural research. Make your contribution to the nanotechnology revolution.



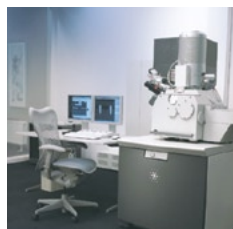
Helios NanoLab™

Sub-nanometer field emission SEM meets next generation FIB. Nano-pioneering the next generation.



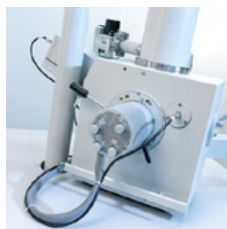
Quanta™ Series

Flexible SEM, FEG SEM and DualBeam™ solutions for structural diagnostics. Any sample, all data, anywhere.



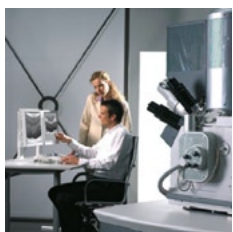
Strata™ DB (STEM)

Delivers integrated sample preparation, ultra-high resolution STEM imaging and microanalysis below 1nm, for high throughput semiconductor and data storage labs. SEM-TEM bridge tool.



Inspect Series

Low-vacuum SEM, FEG SEM for high-resolution material inspection and characterization. Partnership begins here.



Nova™ NanoLab Series

DualBeam™ (SEM/FIB) solution for 3D characterization, prototyping, machining and analysis of structures smaller than 100nm. Make your contribution to the nanotechnology revolution.



Phenom™

A high resolution desktop system ideal for a variety of applications requiring detailed, high magnification images. Its affordable price and intuitive design makes high-end imaging practical for users of all levels.

FEI Company

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Find your Phenom contact information on

www.fei.com/phenom

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 **FEI COMPANY™**
TOOLS FOR NANOTECH